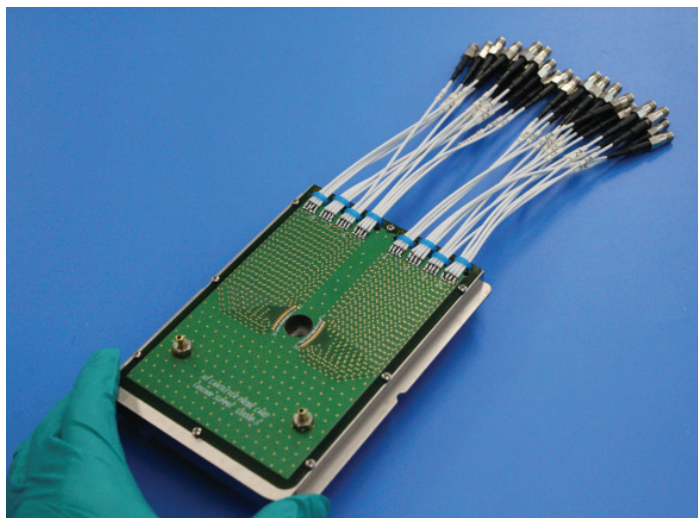


MODELING & CHARACTERIZATION

T40 SERIES

Collect low leakage, low noise, fast settling, and wide operating temperature range measurements with the industry-standard 4.5" compatible T40™ probe card. Patented ceramic holds probes in place and ensures peak electrical performance in a variety of testing environments. The T40™ is crash-resistant - probes stay aligned during crashes, unlike other cards where crashed probes might fall onto your wafer. The T40™ is available in high temperature, Quasi-Kelvin, and AttoFast™ models for ultra-fast femto-amp settling in one second.

The T40™ probe card is optimized to deliver the most accurate low leakage, fast settling, and low noise measurements over a wide temperature range.



SETTING THE
INDUSTRY
STANDARD FOR
ACCURACY